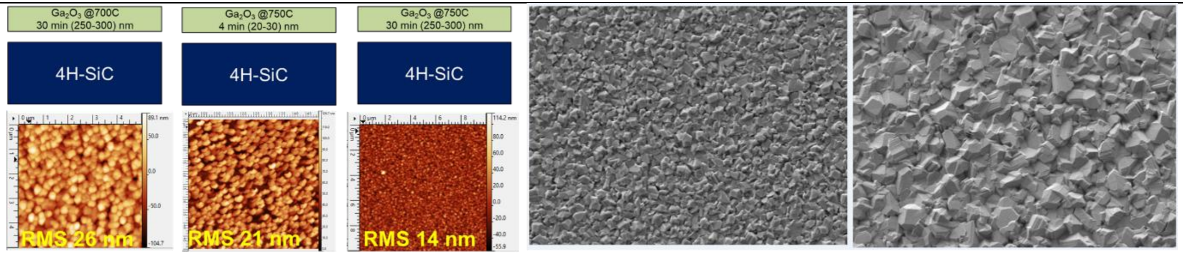

Fig. 1 AFM and FEGSEM surface morphology of samples grown at different temperatures

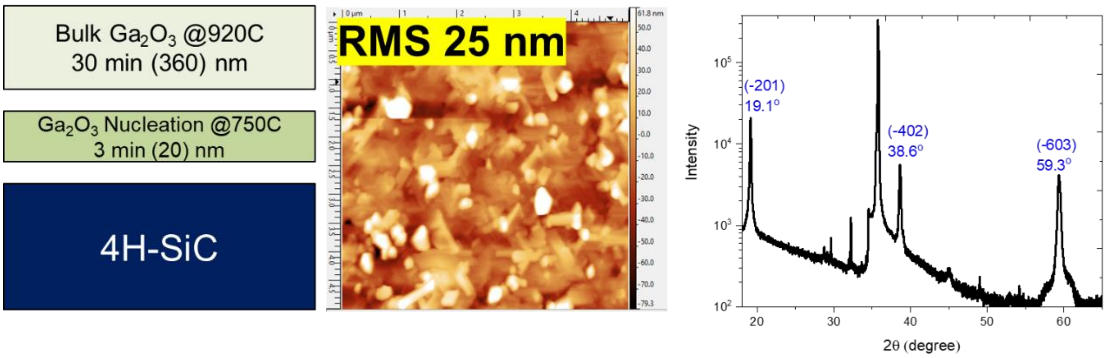

Fig. 2 Showing a schematic of S1 including AFM surface morphology and XRD 2θ-ω scan

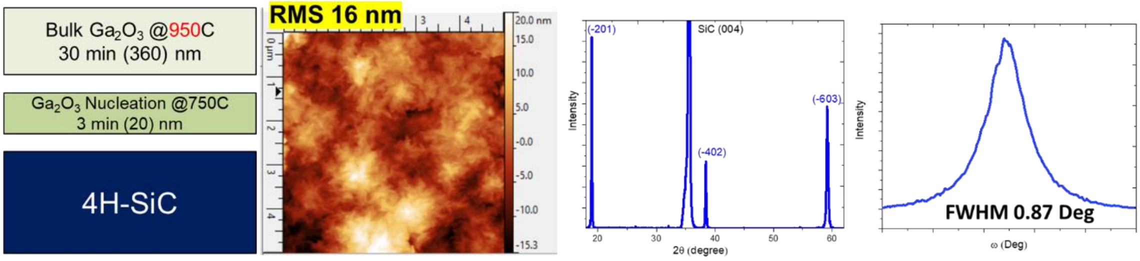

Fig. 3 Shows epitaxial layer schematic of S2 with AFM surface morphology, XRD 2θ-ω scan and FWHM from rocking curve

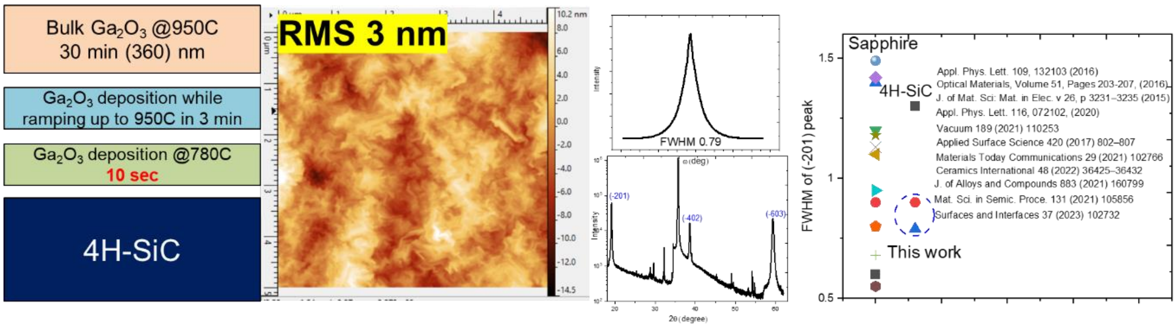

Fig. 4 shows schematic of S3 including with AFM and FEGSEM surface morphology, XRD 2θ-ω scan, FWHM from rocking curve and benchmarking of reported FWHM of MOCVD grown β-Ga_2O_3 on different substrates